Applicant(s)/Patent Under Application/Control No. Reexamination 10/625,738 TACHIBANA ET AL. Notice of References Cited Examiner **Art Unit** Page 1 of 1 2816 Long Nguyen **U.S. PATENT DOCUMENTS** Date **Document Number** Name Classification Country Code-Number-Kind Code MM-YYYY 05-2000 327/91 Α US-6,060,914 Nunokawa, Hideo US-5,880,621 03-1999 Ohashi, Ikuo 326/113 В Ċ 10-1992 327/408 US-5,157,291 Shimoda, Sadashi D US-Ē US-F US-Ġ US-Η US-US-US-US-Κ US-L US-М **FOREIGN PATENT DOCUMENTS** Document Number Country Code-Number-Kind Code Date Classification Country Name MM-YYYY N O Ρ Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

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